



MCM / IC Substrate Test Head

Applications

- Open/short test and contact resistance measurement of multi/single chip module and IC substrate.

Features

- High durability and high performance contact probe assures stable contact resistance.
- Low spring force can prevent any damages to the PCB caused by the mating action.
- Low contact resistance contact probe can meet the minimum pitch (0.1mm) requirement.
- Contact probes can be removed one by one, enabling the user to perform a maintenance.
- Combining suitable size of contact probes enables to reduce the total system cost.

Specifications

	150μm pitch Test Head	100μm pitch Test Head
Block material	Ceramic / Super engineering plastic	Ceramic / Super engineering plastic
Probing area	free to specify	free to specify
Pointing accuracy	± 0.02mm Max.	± 0.01mm Max.
Maximum stroke	0.6mm	0.3mm
Insulation resistance	100MΩ Min.	100MΩ Min.
Probe size	Ø 0.11mm ~ 0.72mm (6sizes)	Ø 0.075mm only
Spring force @2/3 stroke	0.05N ± 0.02N ~ 0.1N ± 0.02N (depend upon probe size)	0.06N ± 0.01